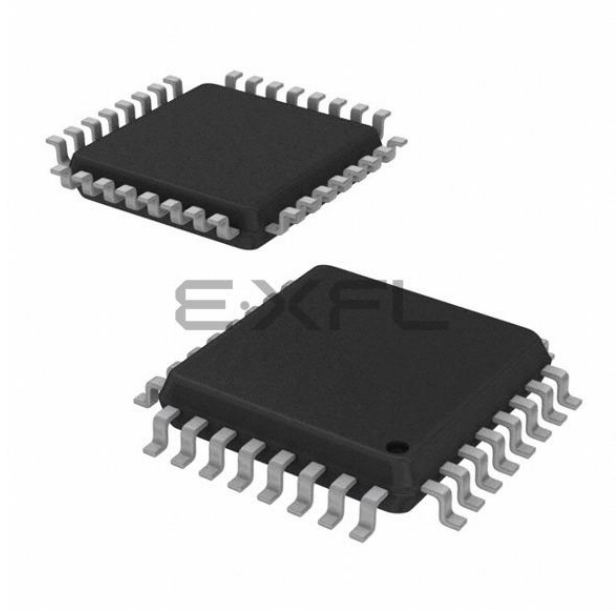

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What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Not For New Designs
Core Processor	STM8
Core Size	8-Bit
Speed	16MHz
Connectivity	I²C, IrDA, LINbus, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, DMA, POR, PWM, WDT
Number of I/O	30
Program Memory Size	16KB (16K x 8)
Program Memory Type	FLASH
EEPROM Size	1K x 8
RAM Size	2K x 8
Voltage - Supply (Vcc/Vdd)	1.65V ~ 3.6V
Data Converters	A/D 22x12b; D/A 1x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 125°C (TA)
Mounting Type	Surface Mount
Package / Case	32-LQFP
Supplier Device Package	32-LQFP (7x7)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm8al3146tcy

List of figures

3.6 LCD (Liquid crystal display)

The liquid crystal display drives up to four common terminals and up to 28 segment terminals to drive up to 112 pixels.

- Internal step-up converter to guarantee contrast control whatever V_{DD}.
- Static 1/2, 1/3, 1/4 duty supported.
- Static 1/2, 1/3 bias supported.
- Phase inversion to reduce power consumption and EMI.
- Up to 4 pixels which can programmed to blink.
- The LCD controller can operate in Halt mode.

Note: Unnecessary segments and common pins can be used as general I/O pins.

3.7 Memories

The medium-density STM8AL313x/4x/6x and STM8AL3L4x/6x devices have the following main features:

- Up to 2 Kbytes of RAM
- The non-volatile memory is divided into three arrays:
  - Up to 32 Kbytes of medium-density embedded Flash program memory
  - 1 Kbytes of Data EEPROM
  - Option bytes.

It supports the read-while-write (RWW): it is possible to execute the code from the program matrix while programming/erasing the data matrix.

The option byte protects part of the Flash program memory from write and readout piracy.

3.8 DMA

A 4-channel direct memory access controller (DMA1) offers a memory-to-memory and peripherals-from/to-memory transfer capability. The 4 channels are shared between the following IPs with DMA capability: ADC1, DAC, I2C1, SPI1, USART1, the 4 Timers.

3.9 Analog-to-digital converter

- 12-bit analog-to-digital converter (ADC1) with 25 channels (including 1 fast channel), temperature sensor and internal reference voltage
- Conversion time down to 1 µs with f_{SYSCLK}= 16 MHz
- Programmable resolution
- Programmable sampling time
- Single and continuous mode of conversion
- Scan capability: automatic conversion performed on a selected group of analog inputs
- Analog watchdog
- Triggered by timer

Note: ADC1 can be served by DMA1.

3.13 Timers

The medium-density STM8AL313x/4x/6x and STM8AL3L4x/6x devices contain one advanced control timer (TIM1), two 16-bit general purpose timers (TIM2 and TIM3) and one 8-bit basic timer (TIM4).

All the timers can be served by DMA1.

Table 3 compares the features of the advanced control, general-purpose and basic timers.

Table 3. Timer feature comparison

Timer	Counter resolution	Counter type	Prescaler factor	DMA1 request generation	Capture/compare channels	Complementary outputs
TIM1	16-bit	up/down	Any integer from 1 to 65536	Yes	3 + 1	3
TIM2			Any power of 2 from 1 to 128		2	None
TIM3						
TIM4	8-bit	up	Any power of 2 from 1 to 32768		0	

3.13.1 TIM1 - 16-bit advanced control timer

This is a high-end timer designed for a wide range of control applications. With its complementary outputs, dead-time control and center-aligned PWM capability, the field of applications is extended to motor control, lighting and half-bridge driver.

- 16-bit up, down and up/down auto reload counter with 16-bit prescaler
- Three independent capture/compare channels (CAPCOM) configurable as input capture, output compare, PWM generation (edge and center aligned mode) and single pulse mode output.
- One additional capture/compare channel which is not connected to an external I/O
- Synchronization module to control the timer with external signals
- Break input to force timer outputs into a defined state
- Three complementary outputs with adjustable dead time
- Encoder mode
- Interrupt capability on various events (capture, compare, overflow, break, trigger)

3.13.2 16-bit general purpose timers

- 16-bit auto reload (AR) up/down-counter
- 7-bit prescaler adjustable to fixed power of 2 ratios (1…128)
- Two individually configurable capture/compare channels
- PWM mode
- Interrupt capability on various events (capture, compare, overflow, break, trigger)
- Synchronization with other timers or external signals (external clock, reset, trigger and enable)

3.16.2 I²C

The I^2C bus interface (I^2C1) provides multi-master capability, and controls all I²C bus-specific sequencing, protocol, arbitration and timing.

- Master, slave and multi-master capability
- Standard mode up to 100 kHz and fast speed modes up to 400 kHz
- 7-bit and 10-bit addressing modes
- SMBus 2.0 and PMBus support
- Hardware CRC calculation

Note: I^2C1 can be served by the DMA1 Controller.

3.16.3 USART

The USART interface (USART1) allows full duplex, asynchronous communications with external devices requiring an industry standard NRZ asynchronous serial data format. It offers a very wide range of baud rates.

- 1 Mbit/s full duplex SCI
- SPI1 emulation
- High precision baud rate generator
- SmartCard emulation
- IrDA SIR encoder decoder
- Single wire half duplex mode

Note: USART1 can be served by the DMA1 Controller.

USART1 can be used to implement LIN slave communication, with LIN Break detection on the framing error flag (FE in USART_SR register) with a value of 0 in the USART data register (USART_DR).

3.17 Infrared (IR) interface

The medium-density STM8AL313x/4x/6x and STM8AL3L4x/6x devices contain an infrared interface which can be used with an IR LED for remote control functions. Two timer output compare channels are used to generate the infrared remote control signals.

3.18 Development support

Development tools

Development tools for the STM8 microcontrollers include:

- The STice emulation system offering tracing and code profiling
- The STVD high-level language debugger including C compiler, assembler and integrated development environment.
- The STVP Flash programming software

The STM8 also comes with starter kits, evaluation boards and low-cost in-circuit debugging/programming tools.

Figure 5. STM8AL31x6T 32-pin pinout (without LCD)

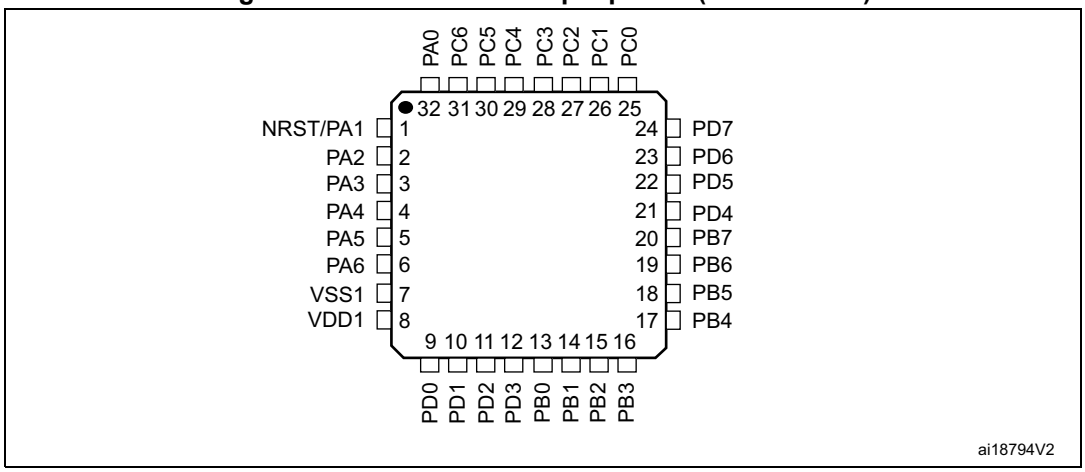


Figure 6. STM8AL3Lx6T 32-pin pinout (with LCD)

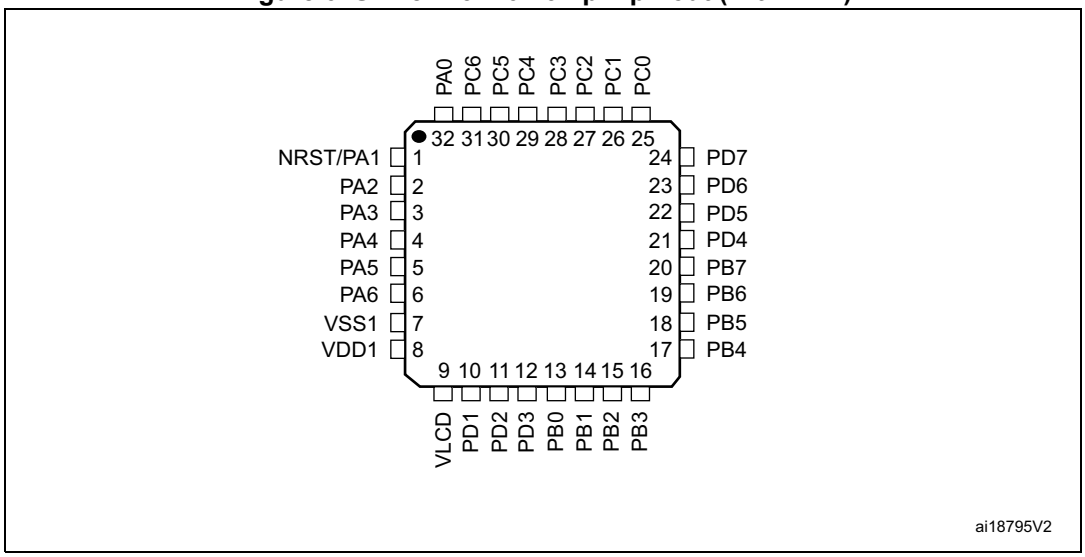


Table 5. Medium-density STM8AL313x/4x/6x and STM8AL3L4x/6x pin description (continued)

Pin number			Pin name	Type	I/O level	Input			Output			Main function (after reset)	Default alternate function
LQFP48	VFQFPN32	LQFP32				floating	wpu	Ext. interrupt	High sink/source	OD	PP		
28	-	-	PB4[6]/*[SPI1_NSS]*[4]/ LCD_SEG14[2]/ ADC1_IN14/COMP1_INP	I/O	TT[3]	X[6]	X[6]	X	HS	X	X	Port B4	*[SPI1 master/slave select]* / LCD segment 14 / ADC1_IN14 / Comparator 1 positive input
-	17	17	PB4[6]/*[SPI1_NSS]*[4]/ LCD_SEG14[2]/ ADC1_IN14/ COMP1_INP/DAC_OUT	I/O	TT[3]	X[6]	X[6]	X	HS	X	X	Port B4	*[SPI1 master/slave select]* / LCD segment 14 / ADC1_IN14 / DAC output / Comparator 1 positive input
29	-	-	PB5/*[SPI1_SCK]*[4]/ LCD_SEG15[2]/ ADC1_IN13/COMP1_INP	I/O	TT[3]	X	X	X	HS	X	X	Port B5	*[SPI1 clock]* / LCD segment 15 / ADC1_IN13 / Comparator 1 positive input
-	18	18	PB5/*[SPI1_SCK]*[4]/ LCD_SEG15[2]/ ADC1_IN13/DAC_OUT/ COMP1_INP	I/O	TT[3]	X	X	X	HS	X	X	Port B5	*[SPI1 clock]* / LCD segment 15 / ADC1_IN13 / DAC output/ Comparator 1 positive input
30	-	-	PB6/[*SPI1_MOSI]*[4]/ LCD_SEG16[2]/ ADC1_IN12/COMP1_INP	I/O	TT[3]	X	X	X	HS	X	X	Port B6	*[SPI1 master out/slave in]*/ LCD segment 16 / ADC1_IN12 / Comparator 1 positive input
-	19	19	PB6/*[SPI1_MOSI]*[4]/ LCD_SEG16[2]/ ADC1_IN12/COMP1_INP /DAC_OUT	I/O	TT[3]	X	X	X	HS	X	X	Port B6	*[SPI1 master out]*/ slave in / LCD segment 16 / ADC1_IN12 / DAC output / Comparator 1 positive input
31	20	20	PB7/*[SPI1_MISO]*[4]/ LCD_SEG17[2]/ ADC1_IN11/COMP1_INP	I/O	TT[3]	X	X	X	HS	X	X	Port B7	*[SPI1 master in- slave out]* / LCD segment 17 / ADC1_IN11 / Comparator 1 positive input
37	25	25	PC0[5]/I2C1_SDA	I/O	FT	X	-	X		T[7]		Port C0	I2C1 data

Table 6. Flash and RAM boundary addresses

Memory area	Size	Start address	End address
RAM	2 Kbyte	0x00 0000	0x00 07FF
Flash program memory	8 Kbyte	0x00 8000	0x00 9FFF
	16 Kbyte		0x00 BFFF
	32 Kbyte		

5.2 Register map

Table 7. Factory conversion registers

Address	Block	Register label	Register name	Reset status
0x00 4910	-	VREFINT_Factory_CONV(1)	Internal reference voltage factory conversion	0xXX
0x00 4911	-	TS_Factory_CONV_V125(2)	Temperature sensor output voltage	0xXX

1. The VREFINT_Factory_CONV byte represents the 8 LSB of the result of the VREFINT 12-bit ADC conversion performed in factory. The MSB have a fixed value: 0x6.
2. The TS_Factory_CONV_V125 byte represents the 8 LSB of the result of the V125 12-bit ADC conversion performed in factory. The 2 MSB have a fixed value: 0x3.

Table 8. I/O port hardware register map

Address	Block	Register label	Register name	Reset status
0x00 5000	Port A	PA_ODR	Port A data output latch register	0x00
0x00 5001		PA_IDR	Port A input pin value register	0xXX
0x00 5002		PA_DDR	Port A data direction register	0x00
0x00 5003		PA_CR1	Port A control register 1	0x01
0x00 5004		PA_CR2	Port A control register 2	0x00
0x00 5005	Port B	PB_ODR	Port B data output latch register	0x00
0x00 5006		PB_IDR	Port B input pin value register	0xXX
0x00 5007		PB_DDR	Port B data direction register	0x00
0x00 5008		PB_CR1	Port B control register 1	0x00
0x00 5009		PB_CR2	Port B control register 2	0x00
0x00 500A	Port C	PC_ODR	Port C data output latch register	0x00
0x00 500B		PB_IDR	Port C input pin value register	0xXX
0x00 500C		PC_DDR	Port C data direction register	0x00
0x00 500D		PC_CR1	Port C control register 1	0x00
0x00 500E		PC_CR2	Port C control register 2	0x00

Table 9. General hardware register map (continued)

Address	Block	Register label	Register name	Reset status
0x00 50E3 to 0x00 50EF	Reserved area (13 bytes)			
0x00 50F0	BEEP	BEEP_CSR1	BEEP control/status register 1	0x00
0x00 50F1 0x00 50F2		Reserved area (2 bytes)		
0x00 50F3		BEEP_CSR2	BEEP control/status register 2	0x1F
0x00 50F4 to 0x00 513F	Reserved area (76 bytes)			
0x00 5140	RTC	RTC_TR1	Time register 1	0x00
0x00 5141		RTC_TR2	Time register 2	0x00
0x00 5142		RTC_TR3	Time register 3	0x00
0x00 5143		Reserved area (1 byte)		
0x00 5144		RTC_DR1	Date register 1	0x01
0x00 5145		RTC_DR2	Date register 2	0x21
0x00 5146		RTC_DR3	Date register 3	0x00
0x00 5147		Reserved area (1 byte)		
0x00 5148		RTC_CR1	Control register 1	0x00
0x00 5149		RTC_CR2	Control register 2	0x00
0x00 514A		RTC_CR3	Control register 3	0x00
0x00 514B		Reserved area (1 byte)		
0x00 514C		RTC_ISR1	Initialization and status register 1	0x00
0x00 514D		RTC_ISR2	Initialization and Status register 2	0x00
0x00 514E 0x00 514F		Reserved area (2 bytes)		
0x00 5150		RTC_SPRERH(1)	Synchronous prescaler register high	0x00(1)
0x00 5151		RTC_SPRERL(1)	Synchronous prescaler register low	0xFF(1)
0x00 5152		RTC_APRER(1)	Asynchronous prescaler register	0x7F(1)
0x00 5153		Reserved area (1 byte)		
0x00 5154		RTC_WUTRH(1)	Wakeup timer register high	0xFF(1)
0x00 5155		RTC_WUTRL(1)	Wakeup timer register low	0xFF(1)
0x00 5156 to 0x00 5158		Reserved area (3 bytes)		
0x00 5159		RTC_WPR	Write protection register	0x00
0x00 515A 0x00 515B		Reserved area (2 bytes)		

Table 9. General hardware register map (continued)

Address	Block	Register label	Register name	Reset status
0x00 52B6	TIM1	TIM1_SR1	TIM1 status register 1	0x00
0x00 52B7		TIM1_SR2	TIM1 status register 2	0x00
0x00 52B8		TIM1_EGR	TIM1 event generation register	0x00
0x00 52B9		TIM1_CCMR1	TIM1 Capture/Compare mode register 1	0x00
0x00 52BA		TIM1_CCMR2	TIM1 Capture/Compare mode register 2	0x00
0x00 52BB		TIM1_CCMR3	TIM1 Capture/Compare mode register 3	0x00
0x00 52BC		TIM1_CCMR4	TIM1 Capture/Compare mode register 4	0x00
0x00 52BD		TIM1_CCER1	TIM1 Capture/Compare enable register 1	0x00
0x00 52BE		TIM1_CCER2	TIM1 Capture/Compare enable register 2	0x00
0x00 52BF		TIM1_CNTRH	TIM1 counter high	0x00
0x00 52C0		TIM1_CNTRL	TIM1 counter low	0x00
0x00 52C1		TIM1_PSCRH	TIM1 prescaler register high	0x00
0x00 52C2		TIM1_PSCRL	TIM1 prescaler register low	0x00
0x00 52C3		TIM1_ARRH	TIM1 Auto-reload register high	0xFF
0x00 52C4		TIM1_ARRL	TIM1 Auto-reload register low	0xFF
0x00 52C5		TIM1_RCR	TIM1 Repetition counter register	0x00
0x00 52C6		TIM1_CCR1H	TIM1 Capture/Compare register 1 high	0x00
0x00 52C7		TIM1_CCR1L	TIM1 Capture/Compare register 1 low	0x00
0x00 52C8		TIM1_CCR2H	TIM1 Capture/Compare register 2 high	0x00
0x00 52C9		TIM1_CCR2L	TIM1 Capture/Compare register 2 low	0x00
0x00 52CA		TIM1_CCR3H	TIM1 Capture/Compare register 3 high	0x00
0x00 52CB		TIM1_CCR3L	TIM1 Capture/Compare register 3 low	0x00
0x00 52CC		TIM1_CCR4H	TIM1 Capture/Compare register 4 high	0x00
0x00 52CD		TIM1_CCR4L	TIM1 Capture/Compare register 4 low	0x00
0x00 52CE		TIM1_BKR	TIM1 break register	0x00
0x00 52CF		TIM1_DTR	TIM1 dead-time register	0x00
0x00 52D0		TIM1_OISR	TIM1 output idle state register	0x00
0x00 52D1		TIM1_DCR1	DMA1 control register 1	0x00
0x00 52D2		TIM1_DCR2	TIM1 DMA1 control register 2	0x00
0x00 52D3		TIM1_DMA1R	TIM1 DMA1 address for burst mode	0x00
0x00 52D4 to 0x00 52DF	Reserved area (12 bytes)			

Table 10. CPU/SWIM/debug module/interrupt controller registers (continued)

Address	Block	Register Label	Register Name	Reset Status
0x00 7F80	SWIM	SWIM_CSR	SWIM control status register	0x00
0x00 7F81 to 0x00 7F8F	Reserved area (15 bytes)			
0x00 7F90	DM	DM_BK1RE	DM breakpoint 1 register extended byte	0xFF
0x00 7F91		DM_BK1RH	DM breakpoint 1 register high byte	0xFF
0x00 7F92		DM_BK1RL	DM breakpoint 1 register low byte	0xFF
0x00 7F93		DM_BK2RE	DM breakpoint 2 register extended byte	0xFF
0x00 7F94		DM_BK2RH	DM breakpoint 2 register high byte	0xFF
0x00 7F95		DM_BK2RL	DM breakpoint 2 register low byte	0xFF
0x00 7F96		DM_CR1	DM Debug module control register 1	0x00
0x00 7F97		DM_CR2	DM Debug module control register 2	0x00
0x00 7F98		DM_CSR1	DM Debug module control/status register 1	0x10
0x00 7F99		DM_CSR2	DM Debug module control/status register 2	0x00
0x00 7F9A		DM_ENFCTR	DM enable function register	0xFF
0x00 7F9B to 0x00 7F9F	Reserved area (5 bytes)			

1. Accessible by debug module only

Table 11. Interrupt mapping (continued)

IRQ No.	Source block	Description	Wakeup from Halt mode	Wakeup from Active-halt mode	Wakeup from Wait (WFI mode)	Wakeup from Wait (WFE mode)(1)	Vector address
18	COMP1/ COMP2/ ADC1	COMP1 interrupt/ COMP2 interrupt ADC1 end of conversion/ analog watchdog/ overrun interrupt	Yes	Yes	Yes	Yes	0x00 8050
19	TIM2	TIM2 update/overflow/ trigger/break interrupt	-	-	Yes	Yes	0x00 8054
20	TIM2	TIM2 capture/compare interrupt	-	-	Yes	Yes	0x00 8058
21	TIM3	TIM3 update /overflow/ trigger/break interrupt	-	-	Yes	Yes	0x00 805C
22	TIM3	TIM3 capture/compare interrupt	-	-	Yes	Yes	0x00 8060
23	TIM1	TIM1 update /overflow/ trigger/COM	-	-	-	Yes	0x00 8064
24	TIM1	TIM1 capture/compare interrupt	-	-	-	Yes	0x00 8068
25	TIM4	TIM4 update /overflow/ trigger interrupt	-	-	Yes	Yes	0x00 806C
26	SPI1	SPI TX buffer empty/RX buffer not empty/error/wakeup interrupt	Yes	Yes	Yes	Yes	0x00 8070
27	USART1	USART1 transmit data register empty/ transmission complete interrupt	-	-	Yes	Yes	0x00 8074
28	USART 1	USART1 received data ready/overrun error/ idle line detected/parity error/global error interrupt	-	-	Yes	Yes	0x00 8078
29	I^2C1	I^2C1 interrupt(3)	Yes	Yes	Yes	Yes	0x00 807C

1. The Low power wait mode is entered when executing a WFE instruction in Low power run mode. In WFE mode, the interrupt is served if it has been previously enabled. After processing the interrupt, the processor goes back to WFE mode. When the interrupt is configured as a wakeup event, the CPU wakes up and resumes processing.
2. The interrupt from PVD is logically OR-ed with Port E and F interrupts. Register EXTI_CONF allows to select between Port E and Port F interrupt (see *External interrupt port select register (EXTI_CONF)* in STM8L051/L052 Value Line, STM8L151/L152, STM8L162, STM8AL31, STM8AL3L MCU lines reference manual (RM0031).
3. The device is woken up from Halt or Active-halt mode only when the address received matches the interface address.

Table 29. Current consumption under external reset

Symbol	Parameter	Conditions		Typ	Unit
$I_{DD(RST)}$	Supply current under external reset (1)	All pins are externally tied to V_{DD}	V_{DD} = 1.8 V	48	µA
			V_{DD} = 3 V	76	
			V_{DD} = 3.6 V	91	

1. All pins except PA0, PB0 and PB4 are floating under reset. PA0, PB0 and PB4 are configured with pull-up under reset.

9.3.4 Clock and timing characteristics

HSE external clock (HSEBYP = 1 in CLK_ECKCR)

Subject to general operating conditions for V_{DD} and T_A.

Table 30. HSE external clock characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
f_{HSE_ext}	External clock source frequency	-	1(1)	-	16(1)	MHz
V_{HSEH}	OSC_IN input pin high level voltage		0.7 x V_{DD}	-	V_{DD}	V
V_{HSEL}	OSC_IN input pin low level voltage		V_{SS}	-	0.3 x V_{DD}	
$C_{in(HSE)}$	OSC_IN input capacitance	-	-	2.6	-	pF
I_{LEAK_HSE}	OSC_IN input leakage current	$V_{SS} < V_{IN} < V_{DD}$	-	-	±500	nA

1. Guaranteed by design.

LSE external clock (LSEBYP=1 in CLK_ECKCR)

Subject to general operating conditions for V_{DD} and T_A.

Table 31. LSE external clock characteristics

Symbol	Parameter	Min	Typ	Max	Unit
f_{LSE_ext}	External clock source frequency	-	32.768	-	kHz
V_{LSEH}	OSC32_IN input pin high level voltage	0.7 x V_{DD}(1)	-	V_{DD}(1)	V
V_{LSEL}	OSC32_IN input pin low level voltage	V_{SS}(1)	-	0.3 x V_{DD}(1)	
$C_{in(LSE)}$	OSC32_IN input capacitance	-	0.6	-	pF
I_{LEAK_LSE}	OSC32_IN input leakage current	-		±500	nA

1. Guaranteed by characterization results.

Table 38. Flash program memory

Symbol	Parameter	Conditions	Min	Max	Unit
T_{WE}	Temperature for writing and erasing	-	-40	125	°C
N_{WE}	Flash program memory endurance (erase/write cycles)(1)	T_A = 25 °C	1000	-	cycles
t_{RET}	Data retention time	T_A = 25 °C	40	-	years
		T_A = 55 °C	20	-	

1. The physical granularity of the memory is four bytes, so cycling is performed on four bytes even when a write/erase operation addresses a single byte.

Data memory

Table 39. Data memory

Symbol	Parameter	Conditions	Min	Max	Unit
T_{WE}	Temperature for writing and erasing	-	-40	125	°C
N_{WE}	Data memory endurance (erase/write cycles)(1)	T_A = 25 °C	300 k	-	cycles
		T_A = -40 to 125 °C	100 k(2)	-	
t_{RET}	Data retention time	T_A = 25 °C	40(2)(3)	-	years
		T_A = 55 °C	20(2)(3)	-	

1. The physical granularity of the memory is four bytes, so cycling is performed on four bytes even when a write/erase operation addresses a single byte.
2. More information on the relationship between data retention time and number of write/erase cycles is available in a separate technical document.
3. Retention time for 256B of data memory after up to 1000 cycles at 125 °C.

9.3.6 I/O current injection characteristics

As a general rule, current injection to the I/O pins, due to external voltage below V_{SS} or above V_{DD} (for standard pins) should be avoided during normal product operation. However, in order to give an indication of the robustness of the microcontroller in cases when abnormal injection accidentally happens, susceptibility tests are performed on a sample basis during device characterization.

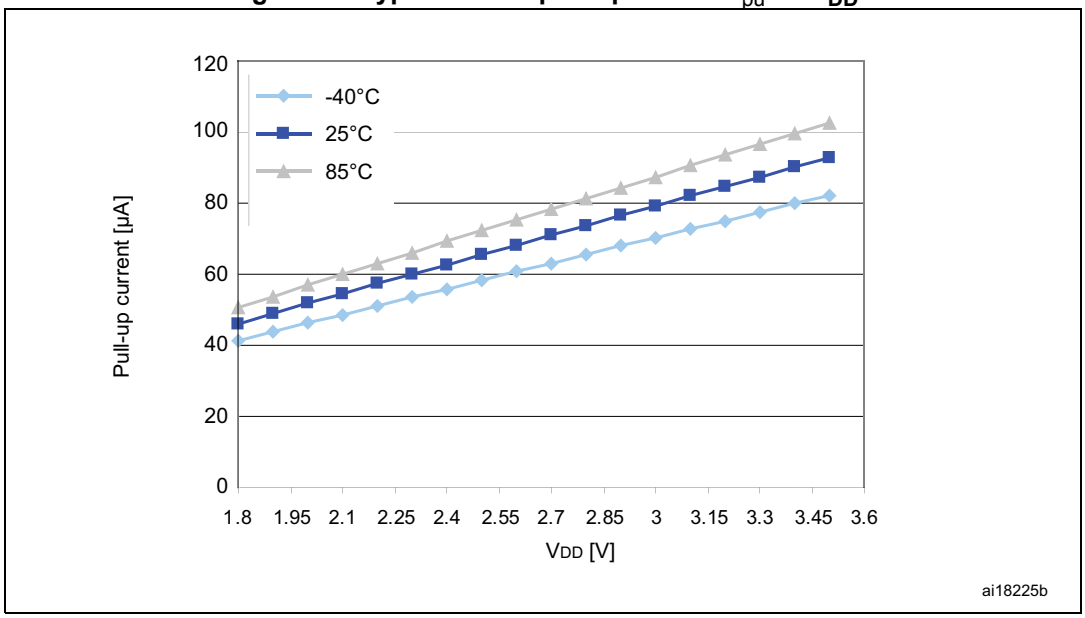
Functional susceptibility to I/O current injection

While a simple application is executed on the device, the device is stressed by injecting current into the I/O pins programmed in floating input mode. While current is injected into the I/O pin, one at a time, the device is checked for functional failures.

The failure is indicated by an out of range parameter: ADC error, out of spec current injection on adjacent pins or other functional failure (for example reset, oscillator frequency deviation, LCD levels, etc.).

The test results are given in the following table.

Figure 30. Typical NRST pull-up current I_{pu} vs V_{DD}



The reset network shown in *Figure 31* protects the device against parasitic resets. The user must ensure that the level on the NRST pin can go below the V_{IL} max. level specified in *Table 45*. Otherwise the reset is not taken into account internally.

For power consumption sensitive applications, the external reset capacitor value can be reduced to limit the charge/discharge current. If the NRST signal is used to reset the external circuitry, attention must be paid to the charge/discharge time of the external capacitor to fulfill the external devices reset timing conditions. The minimum recommended capacity is 10 nF.

Figure 31. Recommended NRST pin configuration

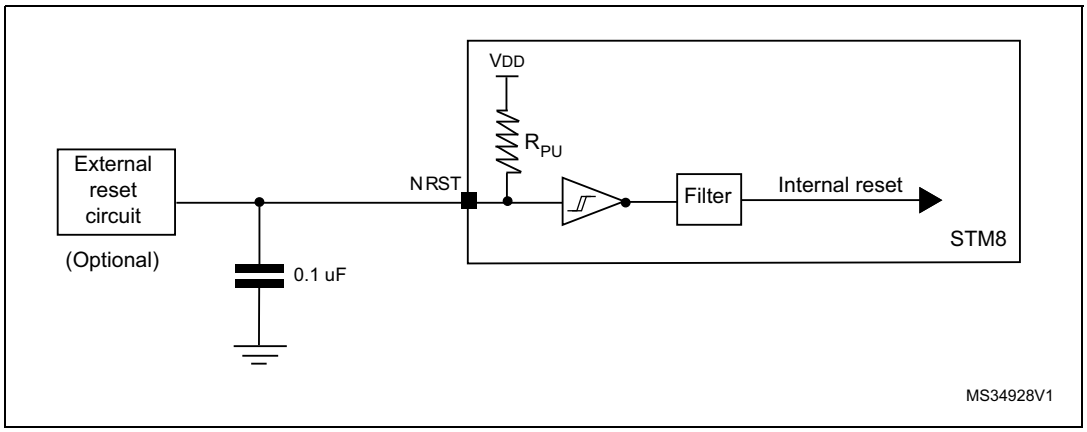


Table 53. DAC characteristics (continued)

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
I_{VREF}	Current consumption on V_{REF+} supply	V_{REF+} = 3.3 V, no load, middle code (0x800)	-	130	220	µA
		V_{REF+} = 3.3 V, no load, worst code (0x000)	-	220	350	
I_{VDDA}	Current consumption on V_{DDA} supply	V_{DDA} = 3.3 V, no load, middle code (0x800)	-	210	320	
		V_{DDA} = 3.3 V, no load, worst code (0x000)	-	320	520	
T_A	Temperature range	-	-40	-	125	°C
R_L	Resistive load(1) (2)	DACOUT buffer ON	5	-	-	kΩ
R_O	Output impedance	DACOUT buffer OFF	-	8	10	
C_L	Capacitive load(3)	-	-	-	50	pF
DAC_OUT	DAC_OUT voltage(4)	DACOUT buffer ON	0.2	-	V_{DDA}-0.2	V
		DACOUT buffer OFF	0	-	V_{REF+} -1 LSB	
$t_{settling}$	Settling time (full scale: for a 12-bit input code transition between the lowest and the highest input codes when DAC_OUT reaches the final value ±1LSB)	$R_L \geq$ 5 kΩ, $C_L \leq$ 50 pF	-	7	12	µs
Update rate	Max frequency for a correct DAC_OUT (@95%) change when small variation of the input code (from code i to i+1LSB).	$R_L \geq$ 5 kΩ, $C_L \leq$ 50 pF	-	-	1	Msps
t_{WAKEUP}	Wakeup time from OFF state. Input code between lowest and highest possible codes.	$R_L \geq$ 5 kΩ, $C_L \leq$ 50 pF	-	9	15	µs
PSRR+	Power supply rejection ratio (to V_{DDA}) (static DC measurement)	$R_L \geq$ 5 kΩ, $C_L \leq$ 50 pF	-	-60	-35	dB

1. Resistive load between DACOUT and GNDA.
2. Output on PF0 (48-pin package only).
3. Capacitive load at DACOUT pin.
4. It gives the output excursion of the DAC.

Electromagnetic interference (EMI)

Based on a simple application running on the product (toggling two LEDs through the I/O ports), the product is monitored in terms of emission. This emission test is in line with the norm IEC61967-2 which specifies the board and the loading of each pin.

Table 62. EMI data (1)

Symbol	Parameter	Conditions	Monitored frequency band	Max vs.	Unit
				16 MHz	
S_{EMI}	Peak level	V_{DD} = 3.6 V, T_A = +25 °C, LQFP32 conforming to IEC61967-2	0.1 MHz to 30 MHz	-3	dBµV
			30 MHz to 130 MHz	9	
			130 MHz to 1 GHz	4	
			EMI Level	2	-

1. Not tested in production.

Absolute maximum ratings (electrical sensitivity)

Based on two different tests (ESD and LU) using specific measurement methods, the product is stressed in order to determine its performance in terms of electrical sensitivity. For more details, refer to the application note AN1181.

Electrostatic discharge (ESD)

Electrostatic discharges (a positive then a negative pulse separated by 1 second) are applied to the pins of each sample according to each pin combination. The sample size depends on the number of supply pins in the device (3 parts*(n+1) supply pin). Two models can be simulated: human body model and charge device model. This test conforms to the ANSI/ESDA/JEDEC JS-001, JESD22-A115 and ANSI/ESD S5.3.1.

Table 63. ESD absolute maximum ratings

Symbol	Ratings	Conditions	Class	Maximum value (1)	Unit
$V_{ESD(HBM)}$	Electrostatic discharge voltage (human body model)	T_A = +25 °C, conforming to ANSI/ESDA/ JEDEC JS-001	2	2000	V
$V_{ESD(CDM)}$	Electrostatic discharge voltage (charge device model)	T_A = +25 °C, conforming to ANSI/ESD S5.3.1	C4B	500	
$V_{ESD(MM)}$	Electrostatic discharge voltage (Machine model)	T_A = +25 °C, conforming to JESD22-A115	M2	200	

1. Guaranteed by characterization results.

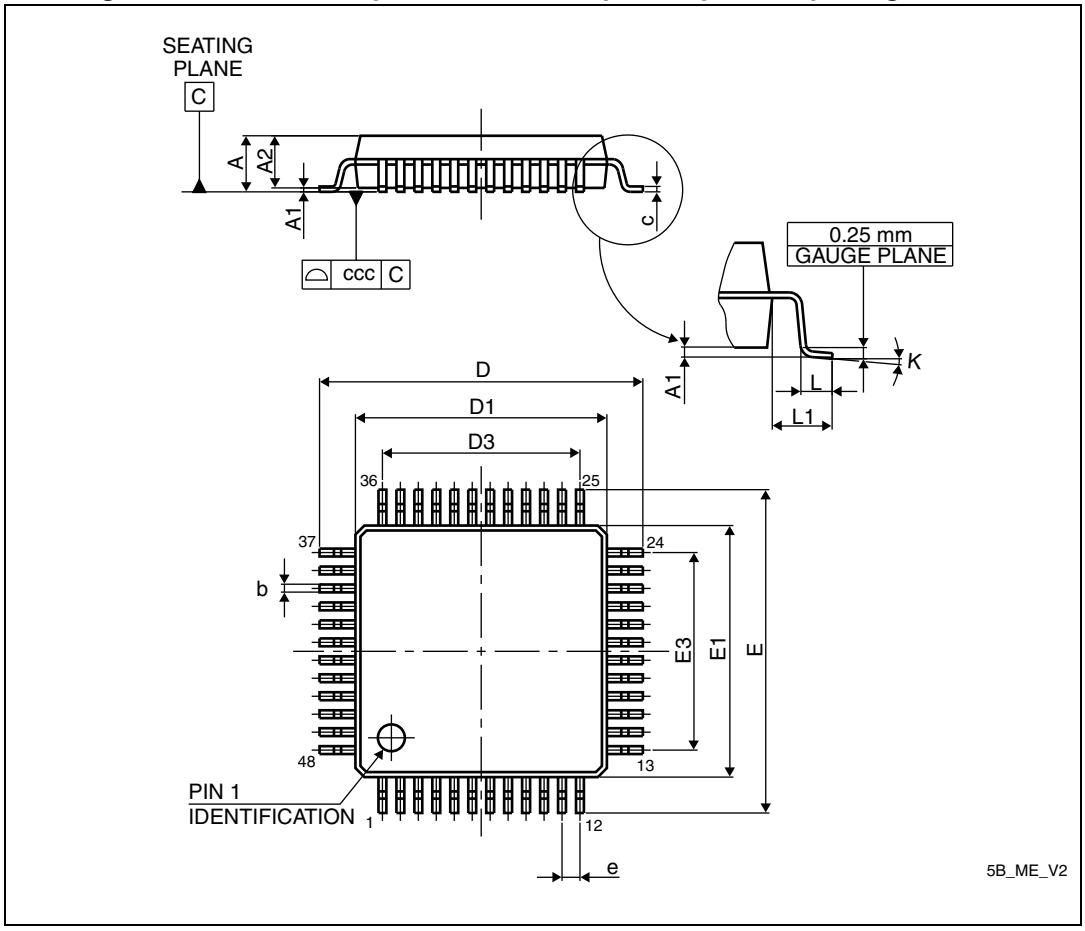
10 Package information

10.1 ECOPACK

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: *www.st.com*. ECOPACK® is an ST trademark.

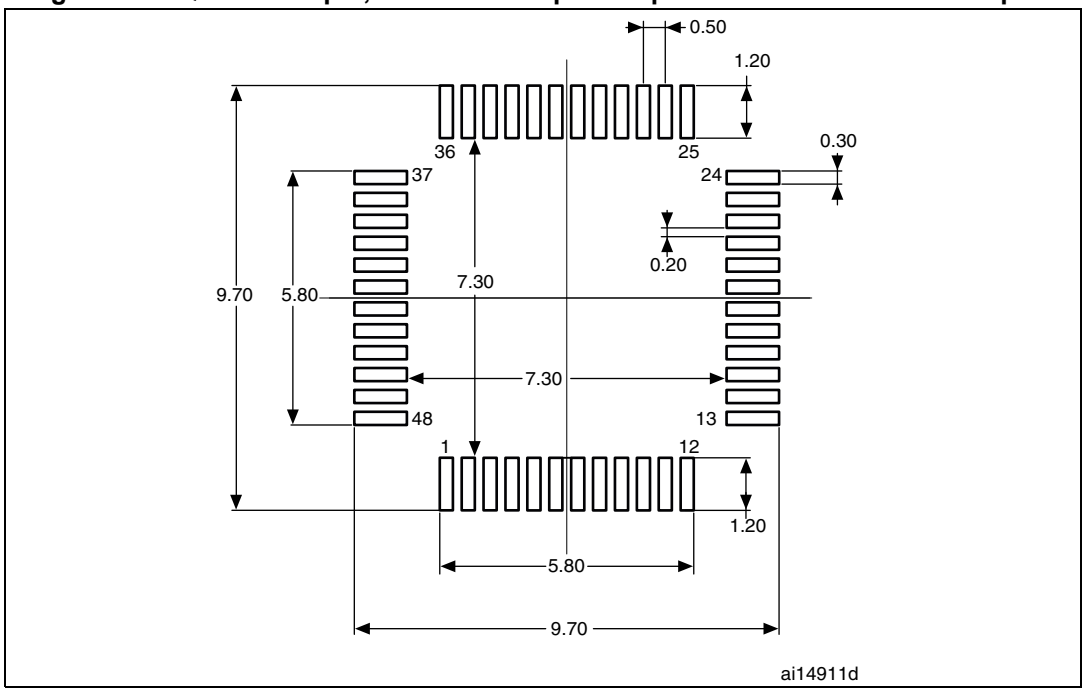
10.2 LQFP48 package information

Figure 41. LQFP48 - 48-pin, 7 x 7 mm low-profile quad flat package outline



1. Drawing is not to scale.

Figure 42. LQFP48 - 48-pin, 7 x 7 mm low-profile quad flat recommended footprint

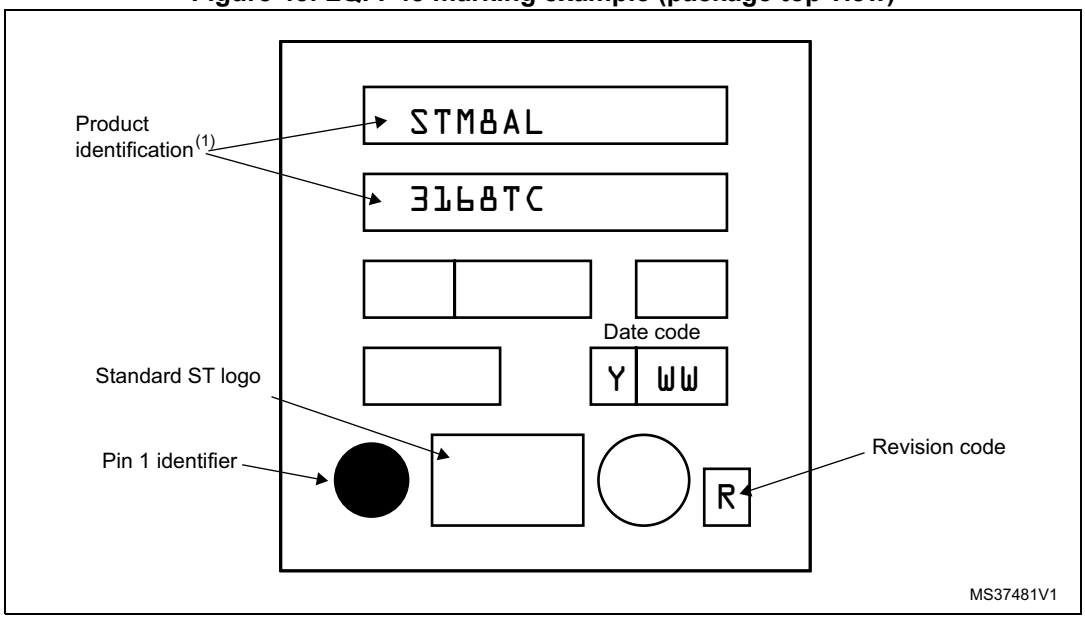


1. Dimensions are expressed in millimeters.

Device marking

The following figure gives an example of topside marking orientation versus pin 1 identifier location.Other optional marking or inset/upset marks, which identify the parts throughout supply chain operations, are not indicated below.

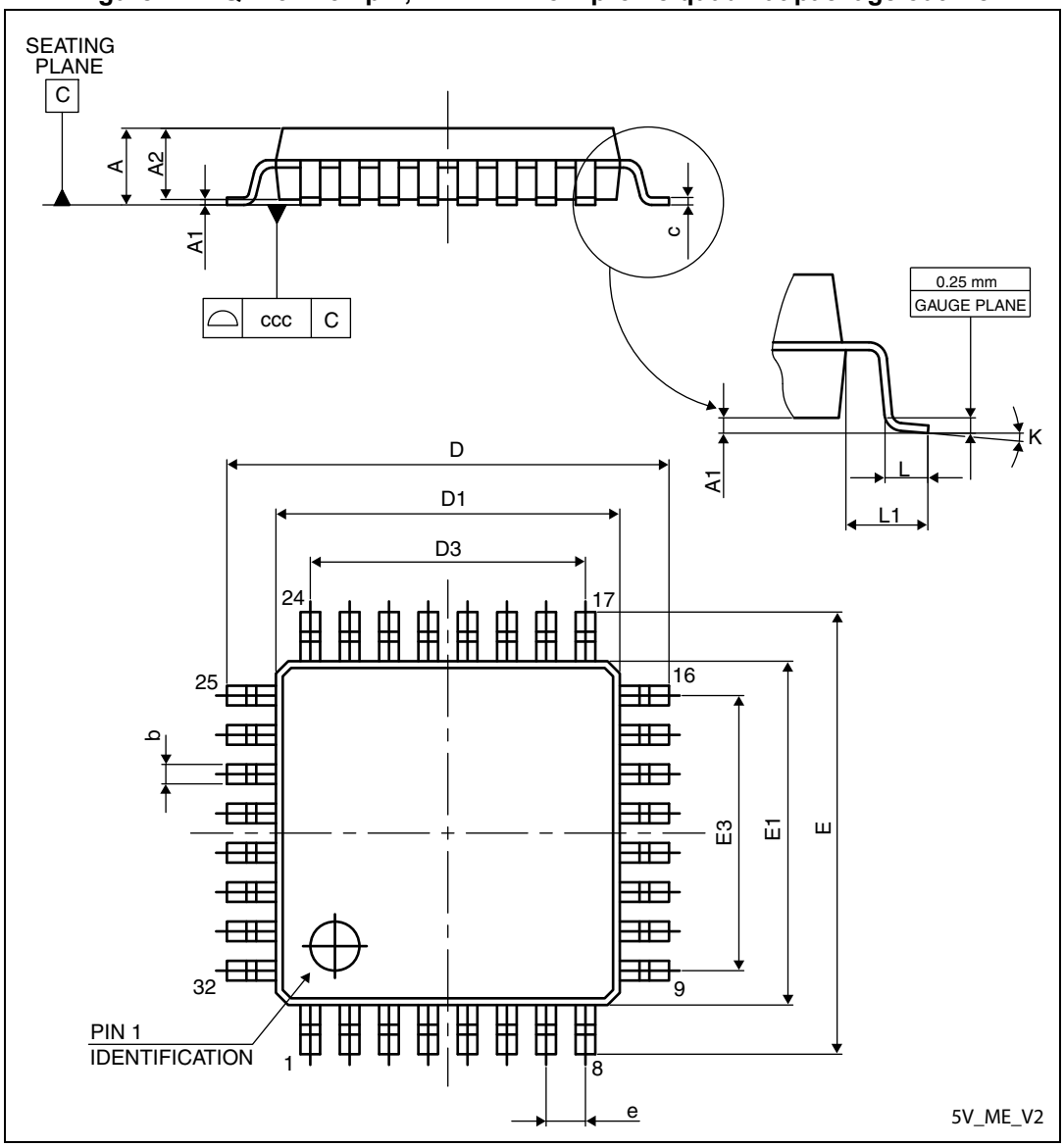
Figure 43. LQFP48 marking example (package top view)



1. Parts marked as “ES” or “E” are not yet qualified and therefore not approved for use in production. ST is not responsible for any consequences resulting from such use. In no event will ST be liable for the customer using any of these engineering samples in production. ST’s Quality department must be contacted prior to any decision to use these engineering samples to run a qualification activity.

10.3 LQFP32 package information

Figure 44. LQFP32 - 32-pin, 7 x 7 mm low-profile quad flat package outline



1. Drawing is not to scale.